

## **OptiMOS™3** Power-Transistor

### **Features**

- MOSFET for ORing and Uninterruptible Power Supply
- Qualified according to JEDEC<sup>1)</sup> for target applications
- N-channel
- Logic level
- Ultra-low on-resistance  $R_{\,\mathrm{DS(on)}}$
- 100% Avalanche tested
- Pb-free plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

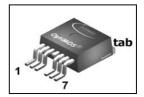




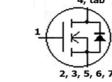
### **Product Summary**

$V_{\mathrm{DS}}$	40	٧
R <sub>DS(on),max</sub>	1.1	mΩ
I <sub>D</sub>	180	Α

### PG-TO263-7



Туре	Package	Marking
IPB011N04L G	PG-TO263-7	011N04L



**Maximum ratings,** at  $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	V <sub>GS</sub> =10 V, T <sub>C</sub> =25 °C	180	Α
		V <sub>GS</sub> =10 V, T <sub>C</sub> =100 °C	180	
		V <sub>GS</sub> =4.5 V, T <sub>C</sub> =25 °C	180	
		V <sub>GS</sub> =4.5 V, T <sub>C</sub> =100 °C	180	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	1260	
Avalanche current, single pulse <sup>3)</sup>	I <sub>AS</sub>	T <sub>C</sub> =25 °C	100	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 Ω	525	mJ
Gate source voltage	V <sub>GS</sub>		±20	٧

<sup>1)</sup> J-STD20 and JESD22



## **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	250	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	

#### Thermal characteristics

Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	0.6	K/W
SMD version, device on PCB	$R_{\mathrm{thJA}}$	minimal footprint	1	1	62	
		6 cm² cooling area <sup>4)</sup>	-	-	40	

## **Electrical characteristics**, at $T_j$ =25 °C, unless otherwise specified

### Static characteristics

		1	_			
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	40	1	1	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 200 \mu{\rm A}$	1.2	1	2	
Zero gate voltage drain current	/ <sub>DSS</sub>	V <sub>DS</sub> =40 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	1	0.1	2	μA
		V <sub>DS</sub> =40 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	20	200	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	1	10	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =100 A	1	1.0	1.4	mΩ
		V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A	-	0.8	1.1	
Gate resistance	R <sub>G</sub>		-	1.5	-	Ω
Transconductance	$g_{ extsf{fs}}$	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =100 A	180	370	-	s

<sup>&</sup>lt;sup>2)</sup> See figure 3 for more detailed information

<sup>&</sup>lt;sup>3)</sup> See figure 13 for more detailed information

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm2 (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	22000	29000	pF
Output capacitance	C oss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =20 V, f=1 MHz	-	4100	5500	
Reverse transfer capacitance	C <sub>rss</sub>		-	240	-	
Turn-on delay time	$t_{d(on)}$		-	25	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =20 V, V <sub>GS</sub> =10 V,	-	13	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_D$ =30 A, $R_G$ =1.6 Ω	-	106	-	1
Fall time	t <sub>f</sub>		-	21	-	
Gate Charge Characteristics <sup>5)</sup>						
Gate to source charge	Q <sub>gs</sub>		-	61	ı	nC
Gate charge at threshold	Q <sub>g(th)</sub>		ı	33	ı	
Gate to drain charge	$Q_{gd}$	V <sub>DD</sub> =20 V, I <sub>D</sub> =100 A,	1	27	-	
Switching charge	Q <sub>sw</sub>	V <sub>GS</sub> =0 to 10 V	1	55	1	
Gate charge total	Qg		1	260	346	
Gate plateau voltage	V <sub>plateau</sub>		-	3.0	-	٧
Gate charge total	Qg	V <sub>DD</sub> =20 V, I <sub>D</sub> =100 A, V <sub>GS</sub> =0 to 4.5 V	-	125	167	nC
Gate charge total, sync. FET	Q <sub>g(sync)</sub>	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 10 V	-	244	-	
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =20 V, V <sub>GS</sub> =0 V	-	153	-	
Reverse Diode	•					•
Diode continuous forward current	Is	T -25 °C	-	-	180	Α
Diode pulse current	I <sub>S,pulse</sub>	− <i>T</i> <sub>C</sub> =25 °C	-	-	1260	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	-	0.82	1.1	V
Reverse recovery charge	Q <sub>rr</sub>	$V_R$ =20 V, $I_F$ = $I_S$ , $di_F/dt$ =400 A/ $\mu$ s	-	120	-	nC

 $<sup>^{5)}\,\</sup>mathrm{See}$  figure 16 for gate charge parameter definition

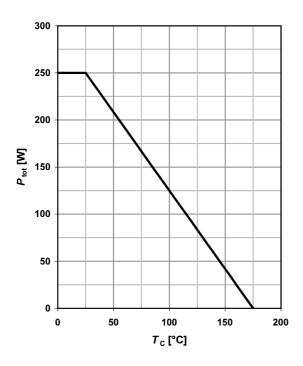


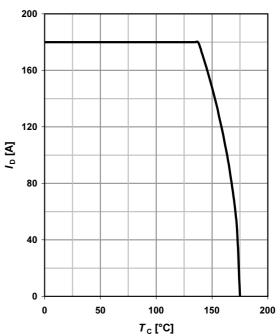
### 1 Power dissipation

# $P_{\text{tot}}$ =f( $T_{\text{C}}$ )

### 2 Drain current

$$I_D=f(T_C); V_{GS} \ge 10 \text{ V}$$





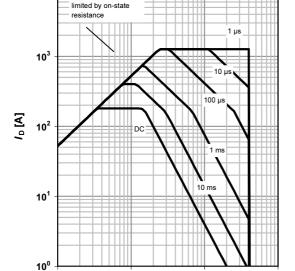
## 3 Safe operating area

$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

parameter:  $t_p$ 

10<sup>4</sup>

10<sup>-1</sup>



10<sup>0</sup>

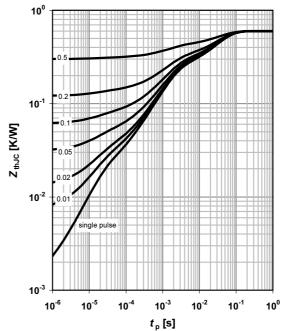
10<sup>1</sup>

 $V_{\rm DS}$  [V]

## 4 Max. transient thermal impedance

$$Z_{thJC}$$
=f( $t_p$ )

parameter:  $D = t_p/T$ 



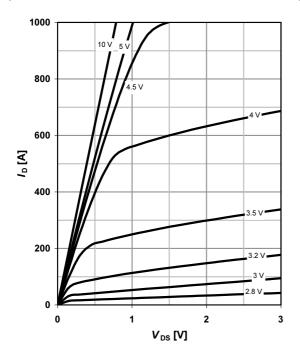
10<sup>2</sup>



### 5 Typ. output characteristics

 $I_D$ =f( $V_{DS}$ );  $T_j$ =25 °C

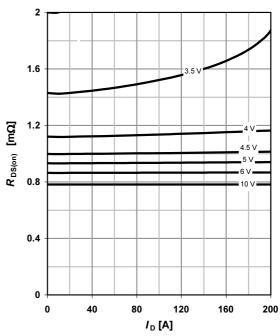
parameter:  $V_{\rm GS}$ 



### 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

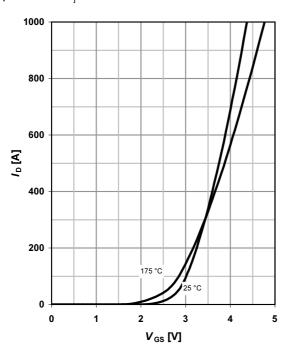
parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

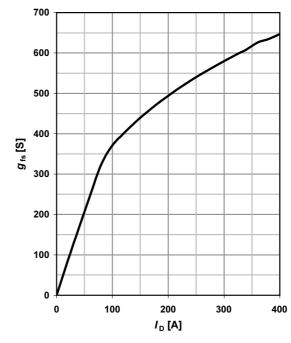
 $I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$ 

parameter:  $T_j$ 



## 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C



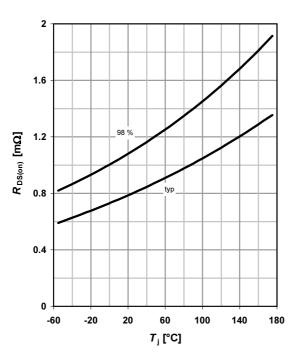


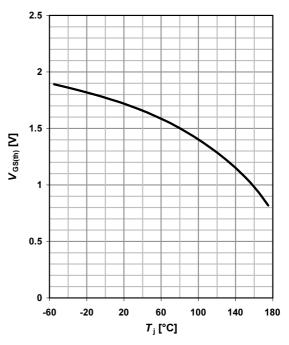
### 9 Drain-source on-state resistance

# $R_{DS(on)}$ =f( $T_j$ ); $I_D$ =100 A; $V_{GS}$ =10 V

## 10 Typ. gate threshold voltage

$$V_{GS(th)}$$
=f( $T_j$ );  $V_{GS}$ = $V_{DS}$ ;  $I_D$ =1mA





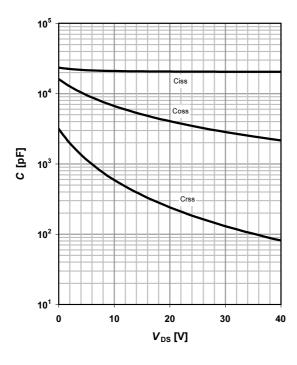
## 11 Typ. capacitances

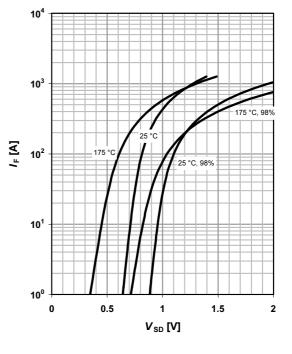
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 

### 12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter:  $T_{\rm j}$ 



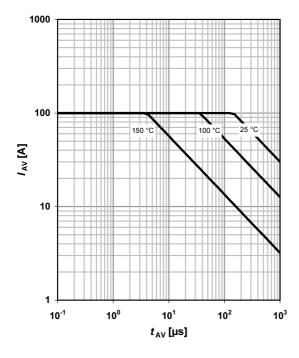




### 13 Avalanche characteristics

 $I_{\mathsf{AS}}$ =f( $t_{\mathsf{AV}}$ );  $R_{\mathsf{GS}}$ =25  $\Omega$ 

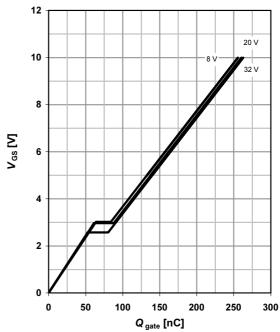
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

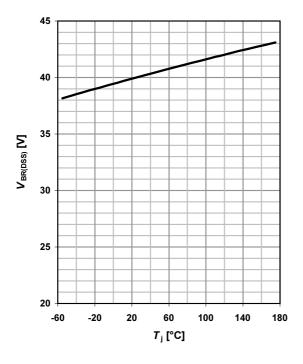
 $V_{\rm GS}$ =f(Q<sub>gate</sub>);  $I_{\rm D}$ =100 A pulsed

parameter: V<sub>DD</sub>

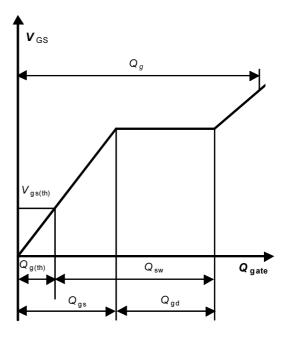


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA



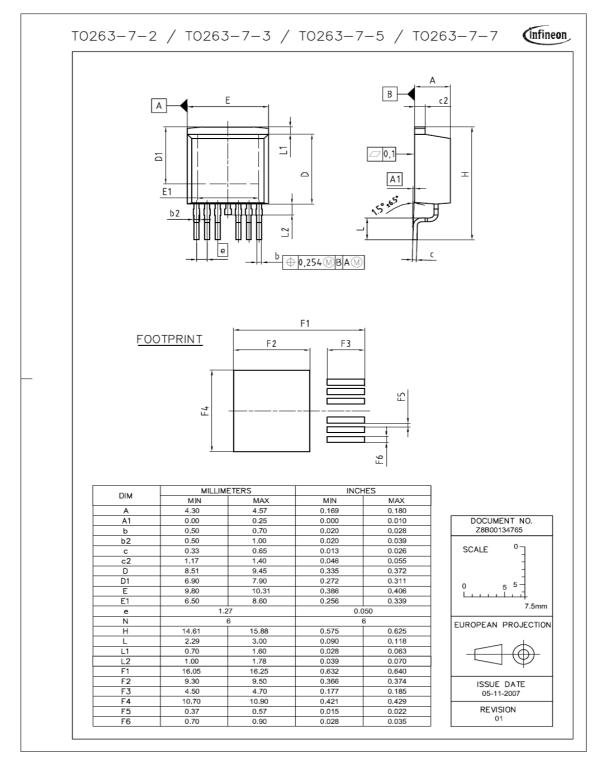
### 16 Gate charge waveforms





### **Package Outline**

### PG-TO263-7





Published by
Infineon Technologies AG
81726 Munich, Germany
© 2009 Infineon Technologies AG
All Rights Reserved.

#### **Legal Disclaimer**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

#### Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

#### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. The Infineon Technologies component described in this Data Sheet may be used in life-support devices or systems and/or automotive, aviation and aerospace applications or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support, automotive, aviation and aerospace device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.